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| Notice of References Cited | Application/Control No. 10/526,465 | | Applicant(s)/Patent Under Reexamination HOUBEN, EWALD | |
| | Examiner CHI Q. NGUYEN | | Art Unit 3635 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | A | US-7,134,805 | 11-2006 | Yee, Alfred A. | 404/50 |
| * | B | US-6,837,013 | 01-2005 | Foderberg et al. | 52/356 |
| * | C | US-6,708,459 | 03-2004 | Bodnar, Ernest R. | 52/356 |
| * | D | US-4,056,908 | 11-1977 | McManus, Ira J. | 52/334 |
| * | E | US-3,956,864 | 05-1976 | Fung, Ching | 52/414 |
| * | F | US-6,000,194 | 12-1999 | Nakamura, Mitsuo | 52/783.17 |
| * | G | US-3,557,511 | 01-1971 | | 52/414 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | |
|---|---|---|--|--|--|
| | U | | | | |
| | V | | | | |
| | W | | | | |
| | X | | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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